

# Search Notes



Application/Control No.

10/643,858

Examiner

J. Pasterczyk

Applicant(s)/Patent under  
Reexamination

CHAN ET AL.

Art Unit

1755

## SEARCHED

Class	Subclass	Date	Examiner
502	102	4/05	JP
	103		
	117		
	153		
	154		
	155		

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
Thurs Search on PALM	4/05	JP